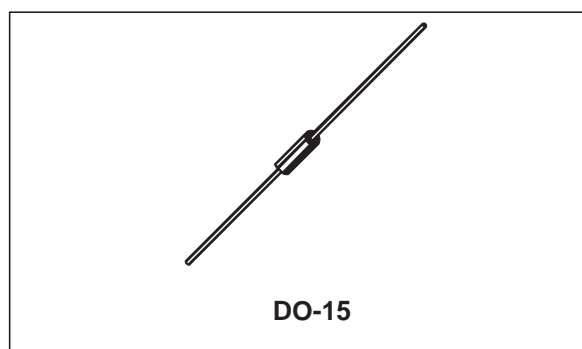


FEATURES

- BIDIRECTIONAL CROWBAR PROTECTION.
- VOLTAGE RANGE: FROM 62 V TO 270 V.
- HOLDING CURRENT :
 $I_H = 150\text{mA min.}$
- REPETITIVE PEAK PULSE CURRENT :
 $I_{PP} = 50\text{ A, } 10/1000\text{ }\mu\text{s.}$

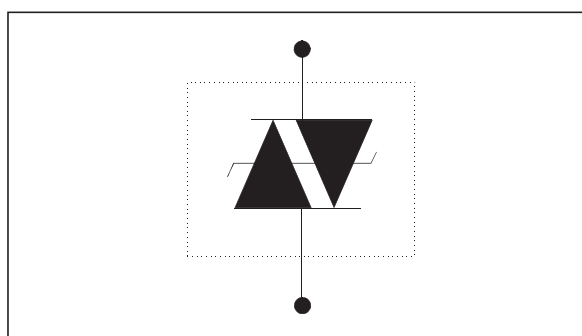


DESCRIPTION

The TPA series are TRISIL devices especially designed for protecting sensitive telecommunication equipment against lightning and transient voltages induced by AC power lines. They are available in the DO-15 axial package.

TRISIL devices provide bidirectional protection by crowbar action. Their characteristic response to transient overvoltages makes them particularly suited to protect voltage sensitive telecommunication equipment.

SCHEMATIC DIAGRAM



COMPLIES WITH THE FOLLOWING STANDARDS:	Peak Surge Voltage (V)	Voltage Waveform (μs)	Current Waveform (μs)	Admissible I_{PP} (A)	Necessary Resistor (Ω)
(CCITT) ITU-K20	1000	10/700	5/310	25	-
(CCITT) ITU-K17	1500	10/700	5/310	38	-
VDE0433	2000	10/700	5/310	50	-
VDE0878	2000	1.2/50	1/20	50	-
IEC-1000-4-5	level 3 level 4	10/700 1.2/50	5/310 8/20	50 100	- -
FCC Part 68, lightning surge type A	1500 800	10/160 10/560	10/160 10/560	75 55	12.5 6.5
FCC Part 68, lightning surge type B	1000	9/720	5/320	25	-
BELLCORE TR-NWT-001089 First level	2500 1000	2/10 10/1000	2/10 10/1000	150 50	11.5 10
BELLCORE TR-NWT-001089 Second level	5000	2/10	2/10	150	11.5
CNET I31-24	1000	0.5/700	0.8/310	25	-

TPA SERIES

ABSOLUTE MAXIMUM RATINGS ($T_{amb} = 25^{\circ}\text{C}$)

Symbol	Parameter		Value	Unit
P	Power dissipation on infinite heatsink	$T_{amb} = 50^{\circ}\text{C}$	1.7	W
I_{PP}	Peak pulse current	10/1000 μs 8/20 μs	50 100	A
I_{TSM}	Non repetitive surge peak on-state current	$t_p = 20\text{ ms}$	30	A
I^2t	I^2t value for fusing	$t_p = 20\text{ ms}$	9	A^2s
dV/dt	Critical rate of rise of off-state voltage	V_{RM}	5	$\text{kV}/\mu\text{s}$
T_{stg} T_j	Storage temperature range Maximum junction temperature		- 55 to + 150 150	$^{\circ}\text{C}$ $^{\circ}\text{C}$

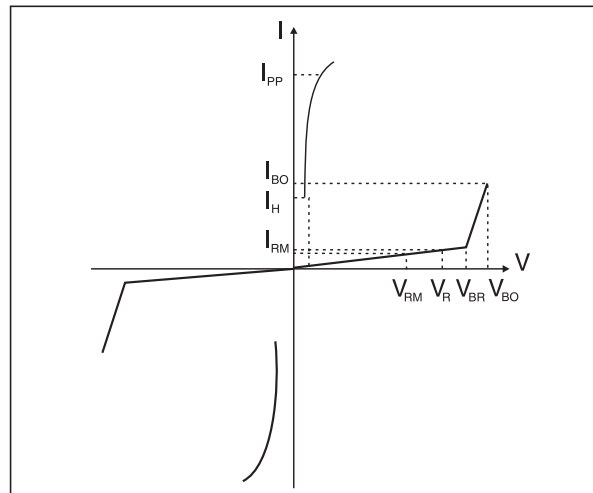
THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
$R_{th(j-l)}$	Junction to leads ($L_{lead} = 10\text{mm}$)		60	$^{\circ}\text{C}/\text{W}$
$R_{th(j-a)}$	Junction to ambient on printed circuit ($L_{lead} = 10\text{ mm}$)		100	$^{\circ}\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS

($T_{amb} = 25^{\circ}\text{C}$)

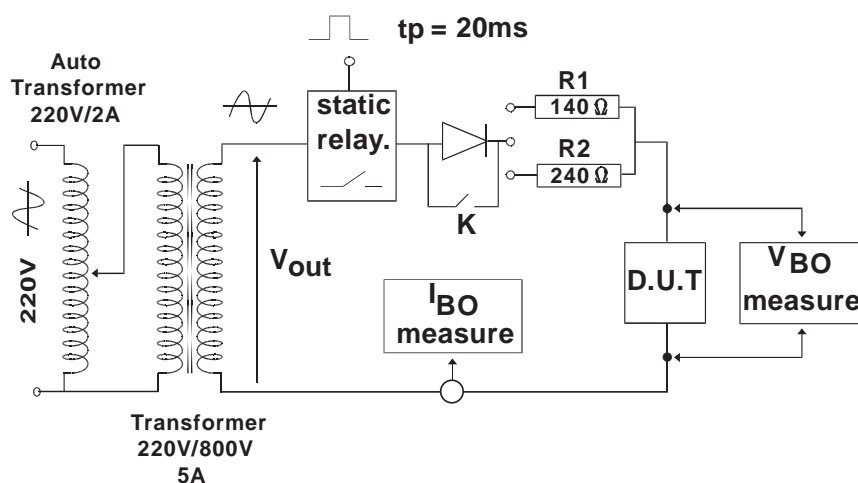
Symbol	Parameter
V_{RM}	Stand-off voltage
I_{RM}	Leakage current at stand-off voltage
V_R	Continuous Reverse voltage
V_{BR}	Breakdown voltage
V_{BO}	Breakover voltage
I_H	Holding current
I_{BO}	Breakover current
I_{PP}	Peak pulse current
C	Capacitance



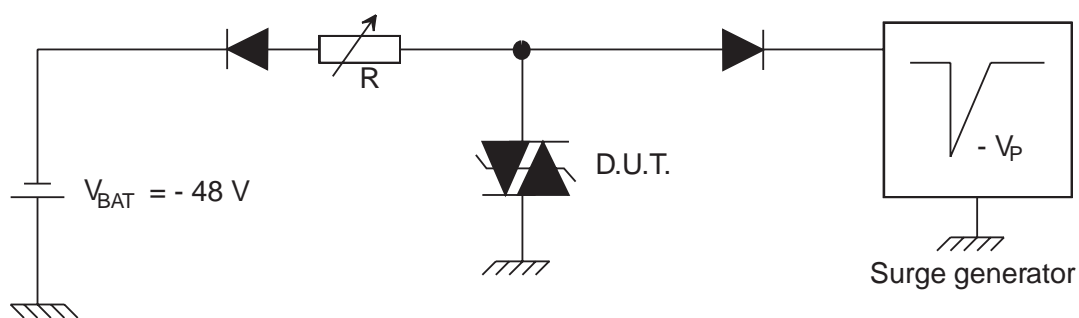
Type	$I_{RM} @ V_{RM}$ max.		$I_R @ V_R$ max. note 1		$V_{BO} @ I_{BO}$ max. note 2		I_H min. note 3	C max. note 4
	μA	V	μA	V	V	mA	mA	pF
TPA62	2	56	50	62	82	800	150	150
TPA68	2	61	50	68	90	800	150	150
TPA100	2	90	50	100	133	800	150	100
TPA120	2	108	50	120	160	800	150	100
TPA130	2	117	50	130	173	800	150	100
TPA180	2	162	50	180	240	800	150	100
TPA200	2	180	50	200	267	800	150	100
TPA220	2	198	50	220	293	800	150	100
TPA240	2	216	50	240	320	800	150	100
TPA270	2	243	50	270	360	800	150	100

Note 1: I_R measured at V_R guarantee V_{BRmin} | V_R
Note 3: See test circuit 2.

Note 2: Measured at 50 Hz (1 cycle) - See test circuit 1.
Note 4: $V_R = 1\text{V}$, $F = 1\text{MHz}$. Refer to fig.3 for C versus V_R .

TEST CIRCUIT 1 FOR I_{BO} and V_{BO} parameters :

TEST PROCEDURE :

- Pulse Test duration ($t_p = 20\text{ms}$):
 - For Bidirectional devices = Switch K is closed
 - For Unidirectional devices = Switch K is open.
- V_{OUT} Selection
 - Device with $V_{BO} < 200$ Volt
 - $V_{OUT} = 250 V_{RMS}$, $R_1 = 140 \Omega$.
 - Device with $V_{BO} \geq 200$ Volt
 - $V_{OUT} = 480 V_{RMS}$, $R_2 = 240 \Omega$.

TEST CIRCUIT 2 for I_H parameter.


This is a GO-NOGO Test which allows to confirm the holding current (I_H) level in a functional test circuit.

TEST PROCEDURE :

- 1) Adjust the current level at the I_H value by short circuiting the AK of the D.U.T.
- 2) Fire the D.U.T with a surge Current : $I_{pp} = 10\text{A}$, $10/1000 \mu\text{s}$.
- 3) The D.U.T will come back off-state within 50 ms max.

TPA SERIES

Fig. 1: Non repetitive surge peak on-state current versus overload duration (T_j initial=25°C).

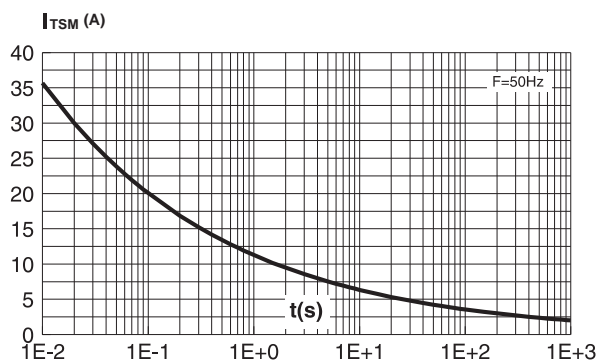


Fig. 3: Relative variation of junction capacitance versus reverse applied voltage (typical values).
Note: For V_{RM} upper than 56V, the curve is extrapolated (dotted line).

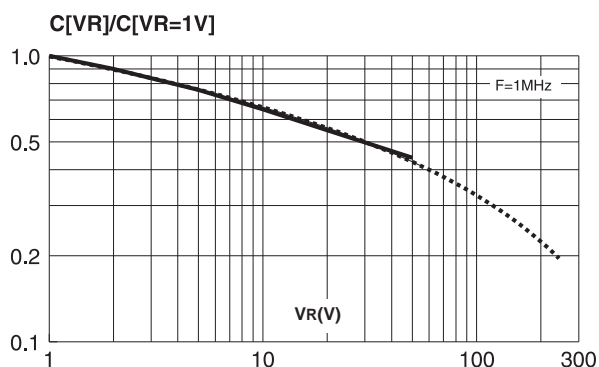


Fig. 5: Transient thermal impedance junction to ambient versus pulse duration (for FR4 PC Board with $T_{lead} = 10$ mm).

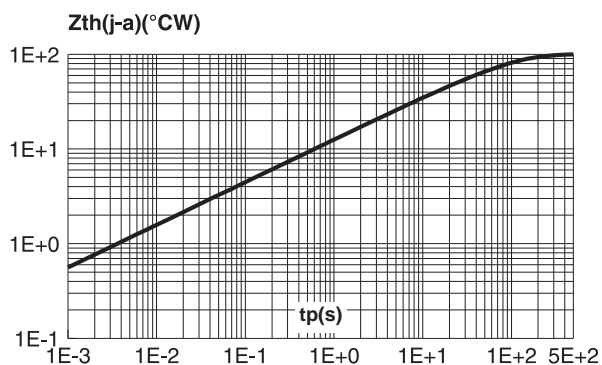


Fig. 2: Relative variation of holding current versus junction temperature.

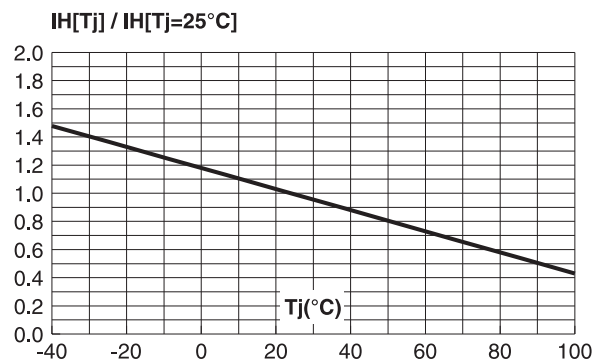
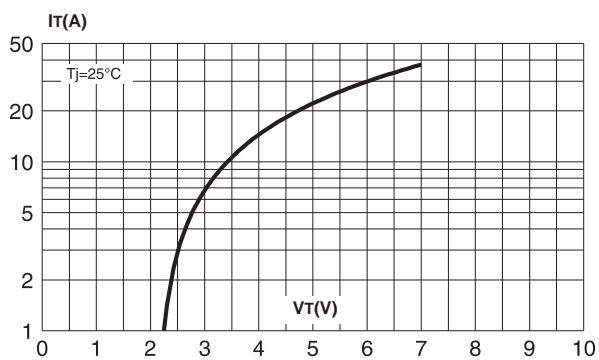
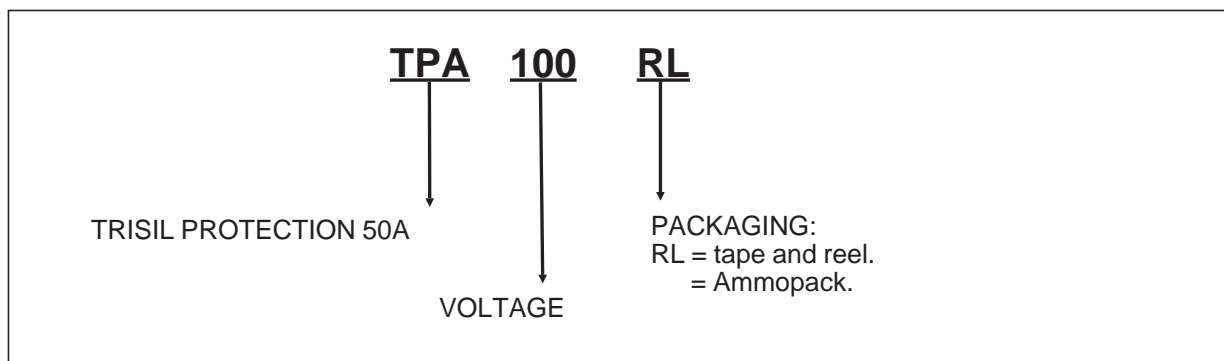


Fig. 4: On-state current versus on-state voltage (typical values).

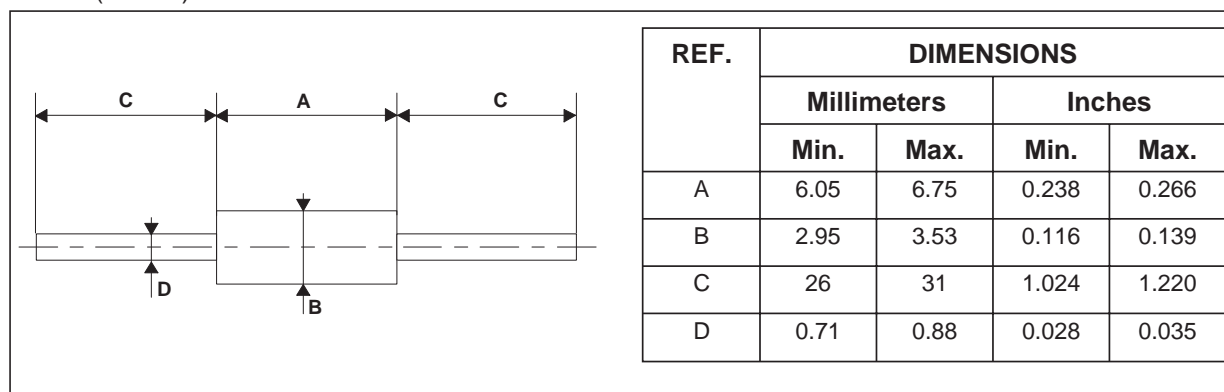


ORDER CODE



MARKING : Logo, Date Code, Part Number.

PACKAGE MECHANICAL DATA
DO-15 (Plastic)



Weight: 0.4 g

Packaging : Standard packaging is in tape and reel.

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